

P30037.A02



U.S. Application No. 10/596,280

IFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s) : Yasuo FUKUDA et al.

Group Art Unit : Not Yet Known

Appln. No. : 10/596,280

Examiner : Not Yet Known

Filed : June 8, 2006

Confirmation No. : 4880

For : EPITAXIAL WAFER AND METHOD FOR PRODUCING SAME

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
U.S. Patent and Trademark Office
Customer Service Window, Mail Stop Amendment
Randolph Building
401 Dulany Street
Alexandria, VA 22314

Sir:

In accordance with the duty of disclosure under 37 C.F.R. §§ 1.56, 1.97, and 1.98, Applicants hereby bring the following information to the attention of the Office, which includes information cited and discussed in the specification, and the International Search Report issued in connection with counterpart International Application No. PCT/JP04/18512. A copy of the International Search Report (in English and Japanese), was enclosed with the papers when entering the National Stage on June 8, 2006. The Examiner is invited to review these materials to inspect the relevance indicated during international examination with respect to the documents cited therein.

The documents are listed below.

1. Semiconductor Silicon Crystal Technology, "VLSI Handbook," Academic Press; 1985, pages 125-128, including a partial English translation; cited and discussed in the specification, beginning at page 1, line 26.

2. JP 9-190979, which was published on July 22, 1997, together with English language family member U.S. Patent No. 6,107,197 to Suzuki, which issued on August 22, 2000;
3. JP 2000-91240, which was published on March 31, 2000, together with English language family member U.S. Patent No. 6,277,657 to Nozawa et al., which issued on August 21, 2001;
4. JP 7-86220, which was published on March 31, 1995, together with an English language machine translation of the same;
5. JP 2000-31071, which was published on January 28, 2000, together with English language family member U.S. Patent No. 6,239,045 to Tanaka et al., which issued on May 29, 2001; and
6. WO 2002/097864 A2 to Brabant et al., which was published on December 5, 2002.

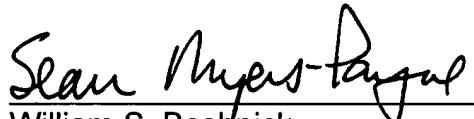
Copies of the above-noted documents, except for U.S. Patents and U.S. Patent Application Publications, are enclosed together with a duly completed Form PTO-1449. The Examiner is accordingly requested to consider each of these documents, and to make them of record in this application by initialing in the appropriate spaces on the Form PTO-1449. Applicant respectfully requests that the Examiner include a copy of the initialed Form PTO-1449 with the next communication from the U.S. Patent and Trademark Office.

Further to the 37 C.F.R § 1.98, copies of the U.S. patents and U.S. published patent applications are not enclosed herewith. However, if any copies are needed, the Examiner is respectfully requested to contact the undersigned.

Applicant notes that an Office Action on the merits has not issued in the present application, and thus no fee is believed necessary to ensure consideration of the submitted material. However, if an Office Action on the merits has issued and is crossing this statement in the mail, the undersigned hereby authorizes the Commissioner to charge any fee necessary for the consideration of this statement, including any payment under 37 C.F.R. §1.17 (p) to Deposit Account No. 19-0089.

Should there be any questions, the Examiner is invited to contact the undersigned at the below listed telephone number.

Respectfully submitted,
Yasuo FUKUDA et al.


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FORM PTO-1449

SEP 20 2006

U.S. Department of Commerce
Patent and Trademark OfficeAtty. Docket No.
P30037Application No.
10/596,280INFORMATIONAL CLOSURE STATEMENT
BY APPLICANT
(Use several sheets if necessary)Applicant
Yasuo FUKUDA et al.Filing Date
June 8, 2006

Group

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		6 1 0 7 1 9 7	08/22/00	SUZUKI			
		6 2 7 7 6 5 7	08/21/01	NOZAWA et al.			
		6 2 3 9 0 4 5	05/29/01	TANAKA et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	9	- 1 9 0 9 7 9	07/22/97	JAPAN			
	2000	- 9 1 2 4 0	03/31/00	JAPAN			
	7	- 8 6 2 2 0	03/31/95	JAPAN			X
	2000	- 3 1 0 7 1	01/28/00	JAPAN			
	2002	/ 0 9 7 8 6 4	12/05/02	W.I.P.O			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

1	Semiconductor Silicon Crystal Technology, "VLSI Handbook," Academic Press; 1985, pages 125-128, including a partial English translation.

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.